

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	49	US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:14
S2	3633	((optical near3 fiber\$1) and defect\$7) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:01
S3	19	((optical near3 fiber\$1) and defect\$7) and filter\$1) and Gabor\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:14
S4	488	machine near3 vision near3 inspection\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:25
S5	2	((machine near3 vision near3 inspection\$1) and filters) and gabor	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:13

S6	122	(machine near3 vision near3 inspection\$1) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:58
S7	48	((machine near3 vision near3 inspection\$1) and filters) and fiber\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:30
S8	8	(machine near3 vision near3 inspection\$1) and (bandpass near3 filters)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:36
S9	2	((optical\$4 near3 fiber\$1) near4 defect\$8) same (bandpass near3 filters)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:43
S10	363	(optical\$3 near3 fiber\$1) near3 inspection	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 15:59
S11	43	((optical\$3 near3 fiber\$1) near3 inspection) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/15 16:09
S12	5366	gabor	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42
S13	128	gabor near2 filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42

S14	2	(gabor near2 filters) and fiber	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:42
S15	193	filters same (fiber\$1 and Defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:45
S16	61	filters same ((optical near3 fiber\$1) and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:50
S17	1855	((optical near3 fiber\$1 near3 end\$1) and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:51
S18	350	(((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:54
S19	168	((((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters) and (spots or scratch\$2 or (cladd\$4 naer3 boundar\$4 near3 defect\$1) or crack\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 14:55
S20	116	((((optical near3 fiber\$1 near3 end\$1) and defect\$1)) and filters) and (spots or scratch\$2 or (cladd\$4 near3 boundar\$4 near3 defect\$1) or crack\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:19
S21	6227	382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:16

S22	2149	382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:29
S23	691	(382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/20 15:30
S24	352	(382/100,141;348/86,88, 125;700/95,142,143;356/73. 1,901,429,430.ccls. and fiber) and filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:14
S25	49	US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:19

S26	6	(US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) and filter\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:15
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S27	43	(US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) not ((US-5179419-\$.DID. OR US-5729622-\$.DID. OR US-5995212-\$.DID. OR US-5535002-\$.DID. OR US-5768409-\$.DID. OR US-5809162-\$.DID. OR US-5600439-\$.DID. OR US-5636020-\$.DID. OR US-5898494-\$.DID. OR US-5671049-\$.DID. OR US-5862250-\$.DID. OR US-5543915-\$.DID. OR US-5768401-\$.DID. OR US-5657131-\$.DID. OR US-5857047-\$.DID. OR US-5857049-\$.DID. OR US-5923781-\$.DID. OR US-5319734-\$.DID. OR US-6105396-\$.DID. OR US-6088498-\$.DID. OR US-6069991-\$.DID. OR US-5729966-\$.DID. OR US-5727327-\$.DID. OR US-5596672-\$.DID. OR US-6183343-\$.DID.) and filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/21 15:19
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S28	60	(digital near3 imag\$3) same (filters and defect\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:24
S29	0	(digital near3 imag\$3) same filters0 and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:25
S30	244	((digital near3 imag\$3) same filters) and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:50
S31	6	((digital near3 imag\$3) same (spatial near3 filters)) and defect\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 10:30
S32	13	spatial near3 bandpass near3 filters	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:05
S33	923	imag\$3 and (spatial near3 filters) and (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:08
S34	426	(imag\$3 same (spatial near3 filters)) and (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:08
S35	68	(imag\$3 same (spatial near3 filters)) same (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:32

S36	72	(imag\$3 same (spatial near3 filters)) same (defect\$6 or scratch\$3 or spot\$1 or crack\$1 or cladd\$4 or flaw\$)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 11:32
S37	5370	GABOR	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:31
S38	213	GABOR NEAR3 FILTER\$1	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:31
S39	115	(GABOR NEAR3 FILTER\$1) and (defect\$1 or flaw\$1 or error\$1 or crack\$1 or scratch\$3 or spot\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/25 12:32
S40	118	image\$1 same (Fourier near3 transform\$3) same ((power near4 two) or (2x2 or 4x4 or 16x16))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/30 13:26
S41	5	interpolat\$6 same (gabor near3 filter\$)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2004/10/30 13:29
S42	2	"6753965".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:16
S43	6649	382/100,141;348/86,88,125;700/95,142,143;356/73.1,901,429,430.ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:38

S44	2	"5995212".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:27
S45	388	S43 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:38
S46	8163	382/100,141,142,143,144, 145,146,147,148,149;348/86, 88,125;700/95,142, 143;356/73.1,901,429,430. ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:02
S47	483	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:36
S48	80	S47 and (("max." maximum max highest most) near6 pixel\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:39
S49	30	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 (bandpass near3 filter\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:48
S50	23	S46 and ((bank set multiple plural\$4 several two three four five six seven) near4 (spatial near3 filter\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:48
S51	503	S46 and ((defect\$3 inspection\$4 deform\$6) same (thread\$1 fiber\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03

S52	48	S51 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:51
S53	48	S51 and ((bank set multiple plural\$4 several two three four five six seven group\$1) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 17:52
S54	2971	356/73.1,239.2,901,429,430. ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S55	183	S54 and ((bank set multiple plural\$4 several two three four five six seven) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S56	22	S55 and ((defect\$3 inspection\$4 deform\$6) same (thread\$1 fiber\$1))	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:03
S57	6	"6636298".pn.",6408429".pn. ",6748104".pn.	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:08
S58	52457	((bandpass Gabor\$1 spatial\$3) near4 filter\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:37
S59	2460	((bandpass Gabor\$1 spatial\$3) near4 filter\$1) same (thread\$1 fiber\$1)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:37

S60	450	S59 and (inspect\$ defect\$5)	US-PGPU B; USPAT; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2005/05/30 18:38
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IEE JNL IEE Journal or Magazine

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